


<b>Search Notes</b>  	<b>Application/Control No.</b>  10085547	<b>Applicant(s)/Patent Under Reexamination</b>  BANTZ ET AL.
	<b>Examiner</b>  Zhen, Li B	<b>Art Unit</b>  2194

SEARCHED			
Class	Subclass	Date	Examiner
717	168, 178	8/30/2007	LZ

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	8/30/2007	LZ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner